

FIG. 1

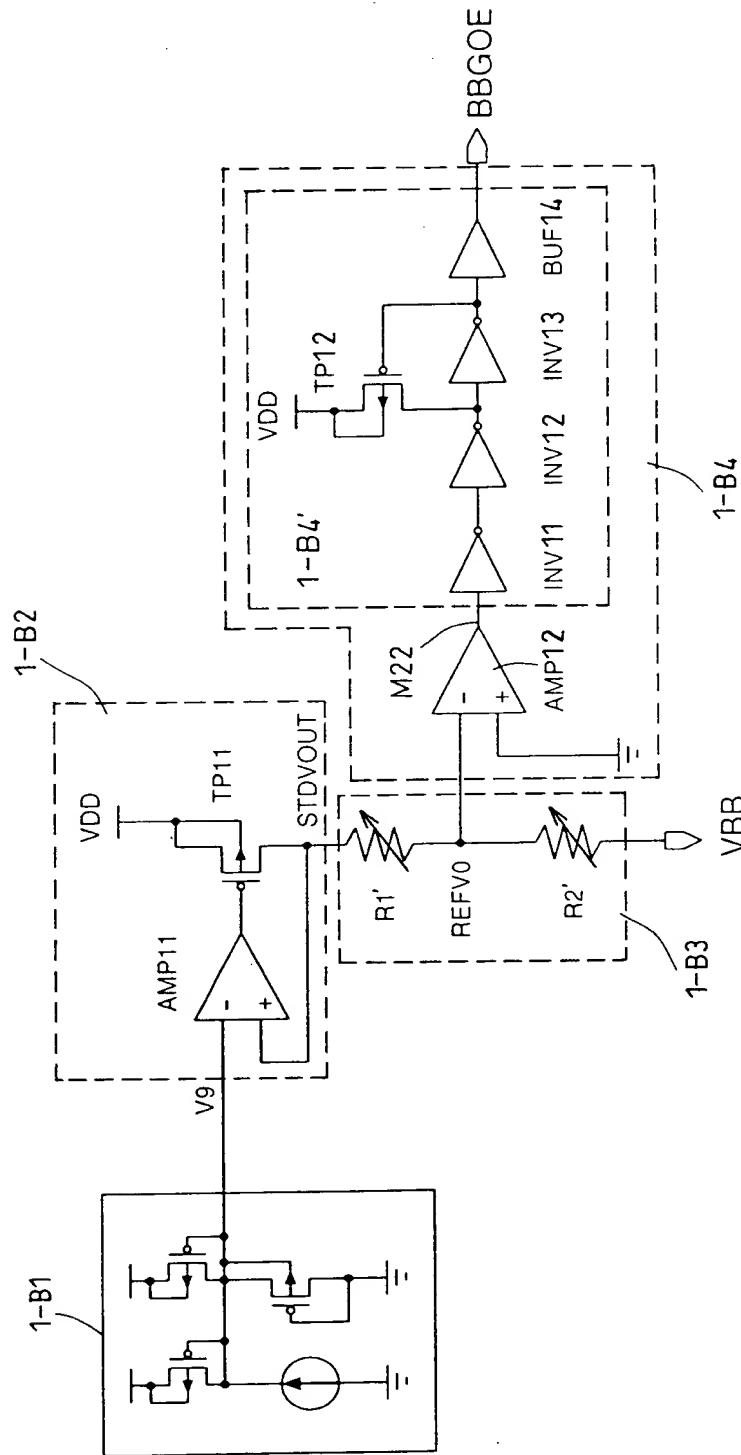


FIG. 2

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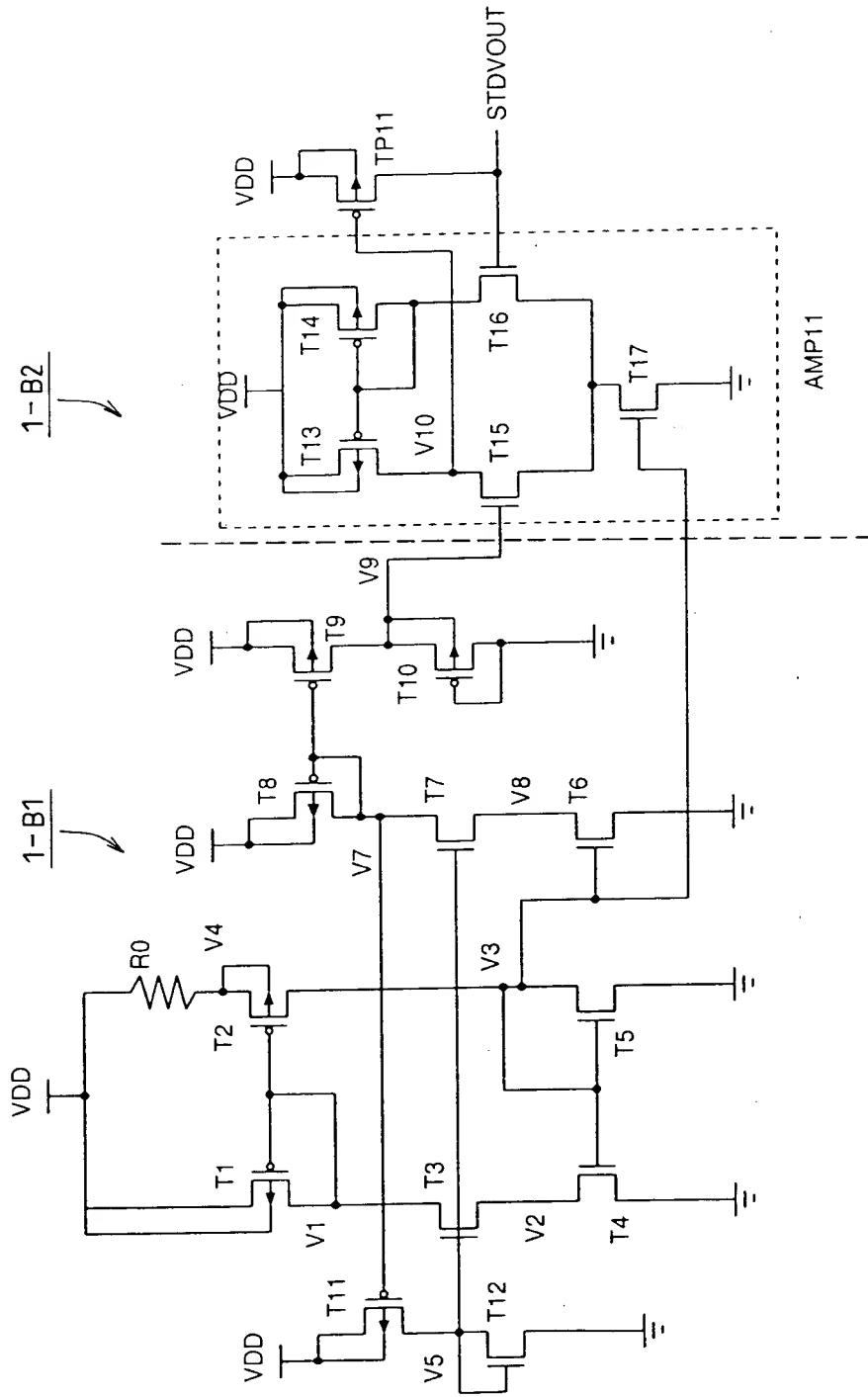


FIG. 3

100150 " 62825360

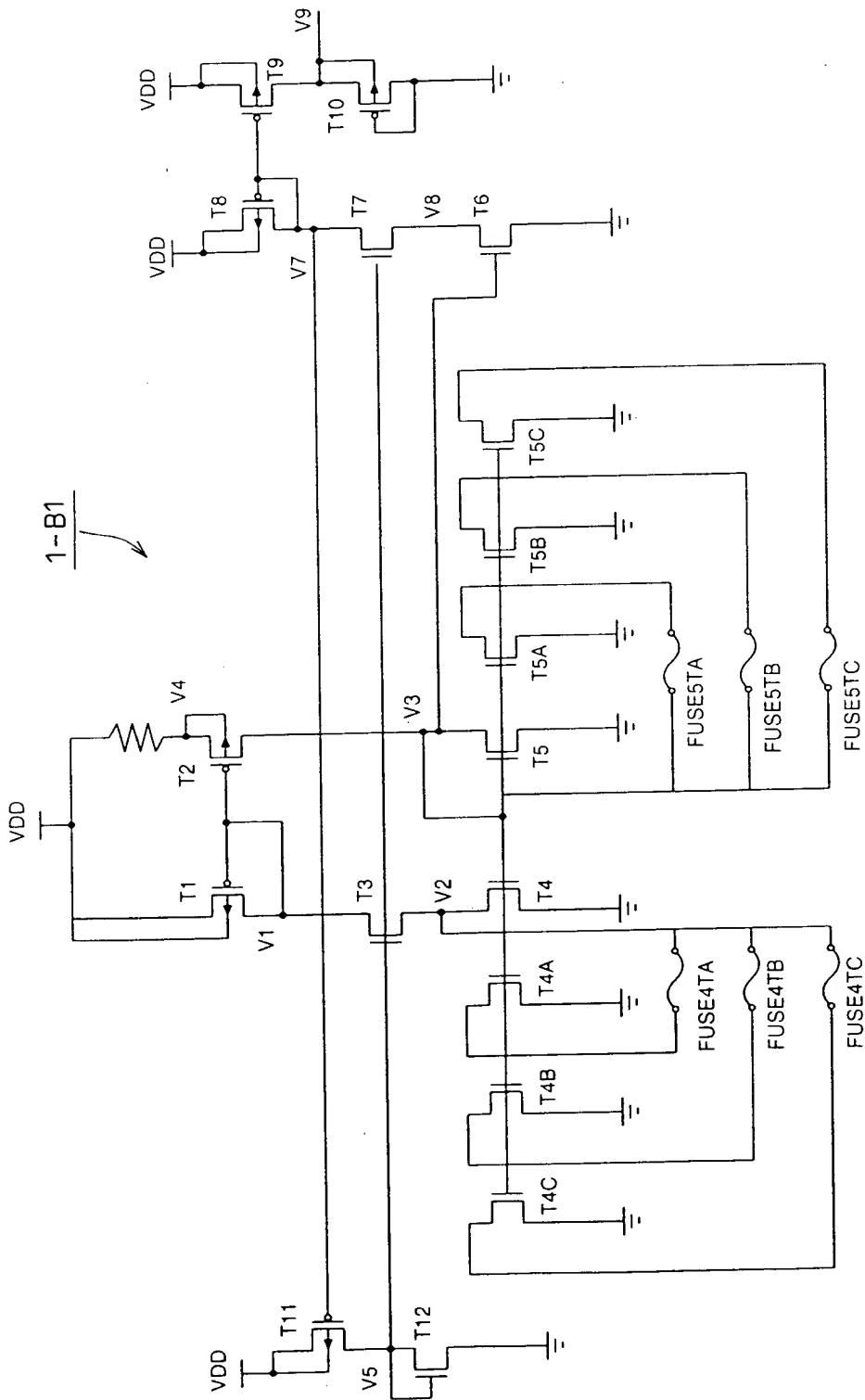


FIG. 4

09256829-051000

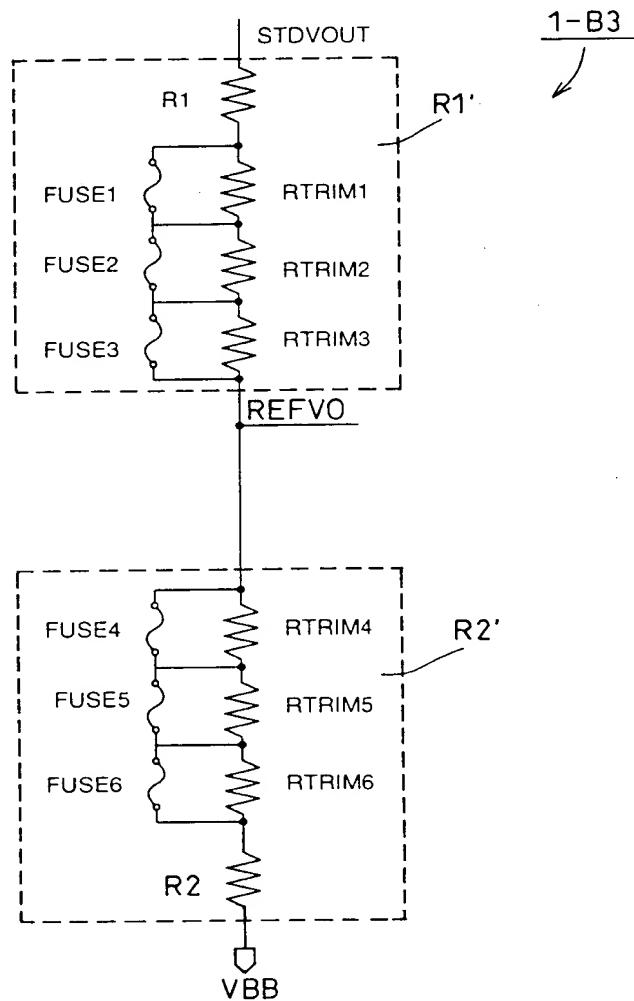


FIG. 5

10011000 01100100 00100000

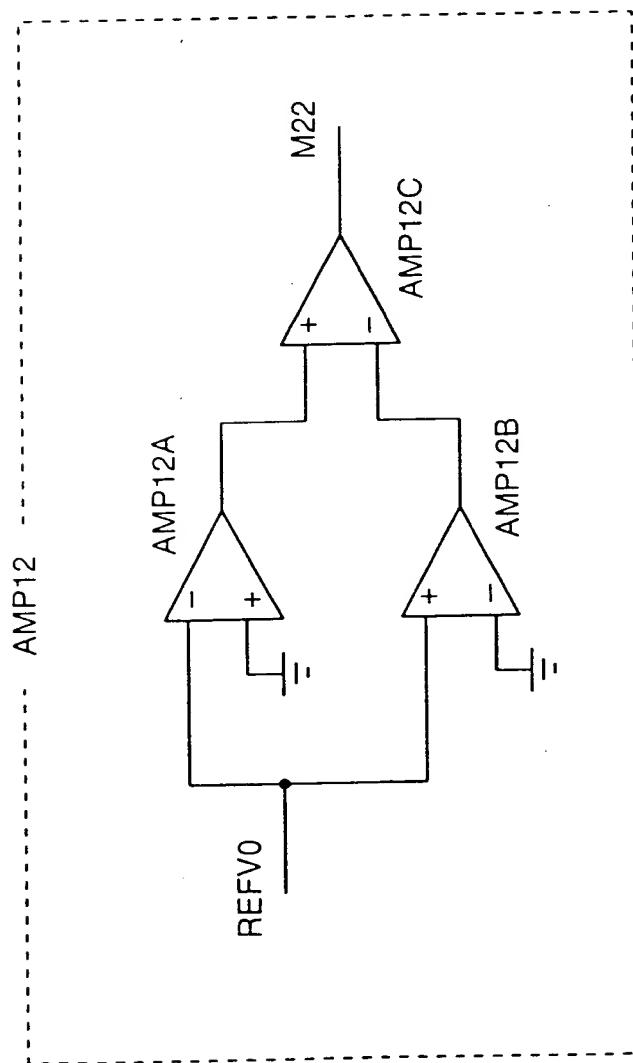


FIG. 6

0 1 2 3 4 5 6 7 8 9 10

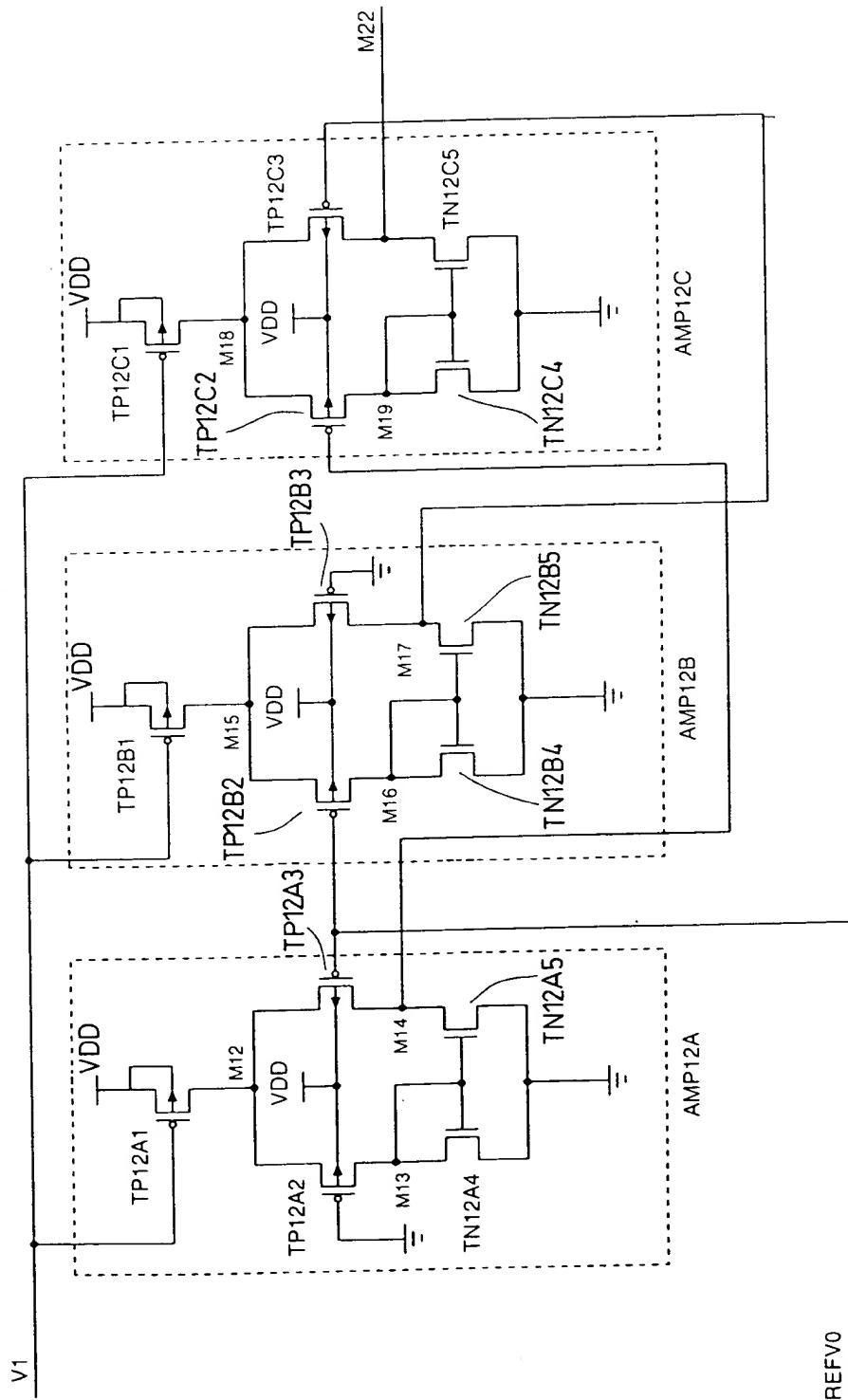


FIG. 7

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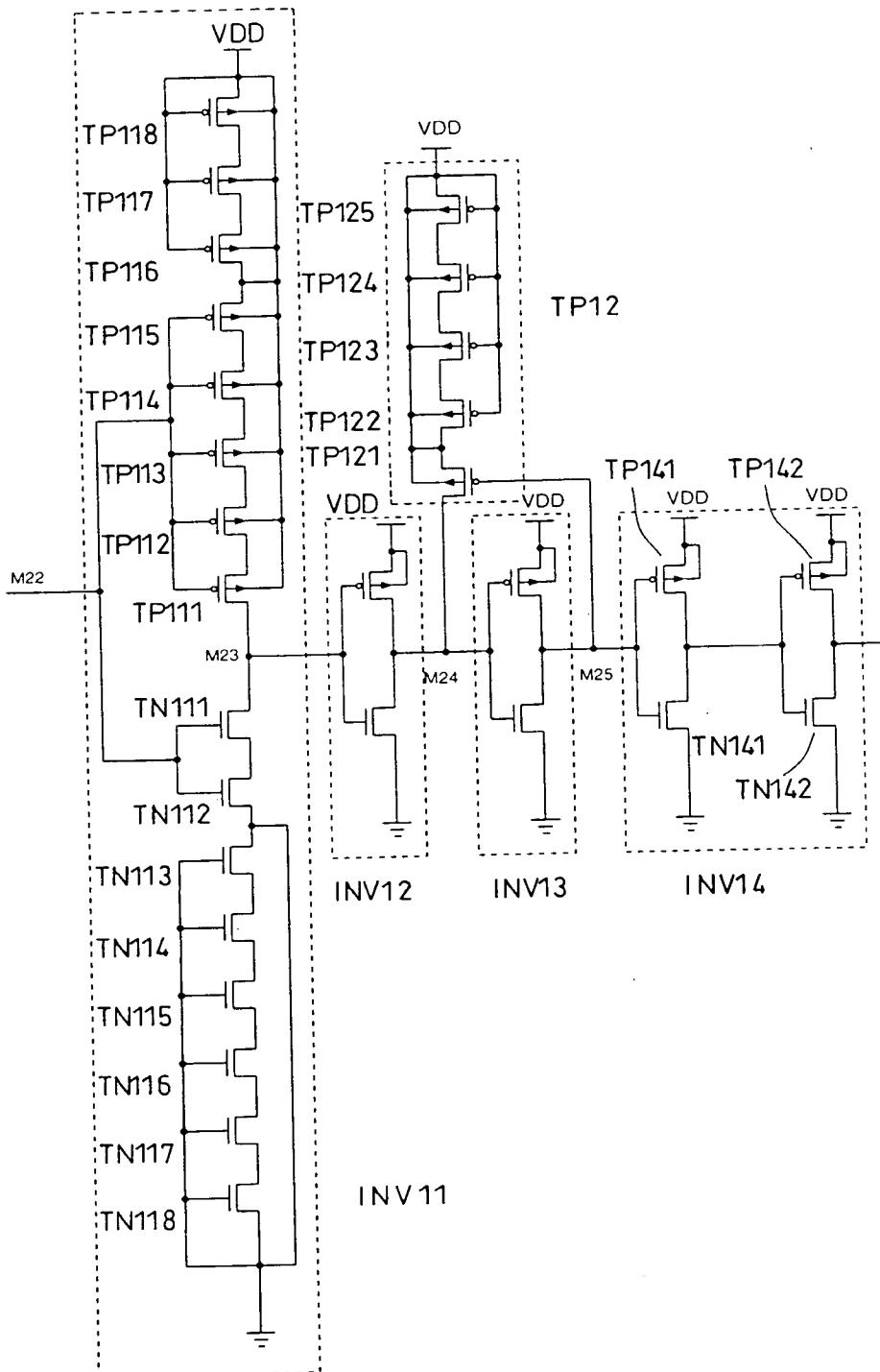
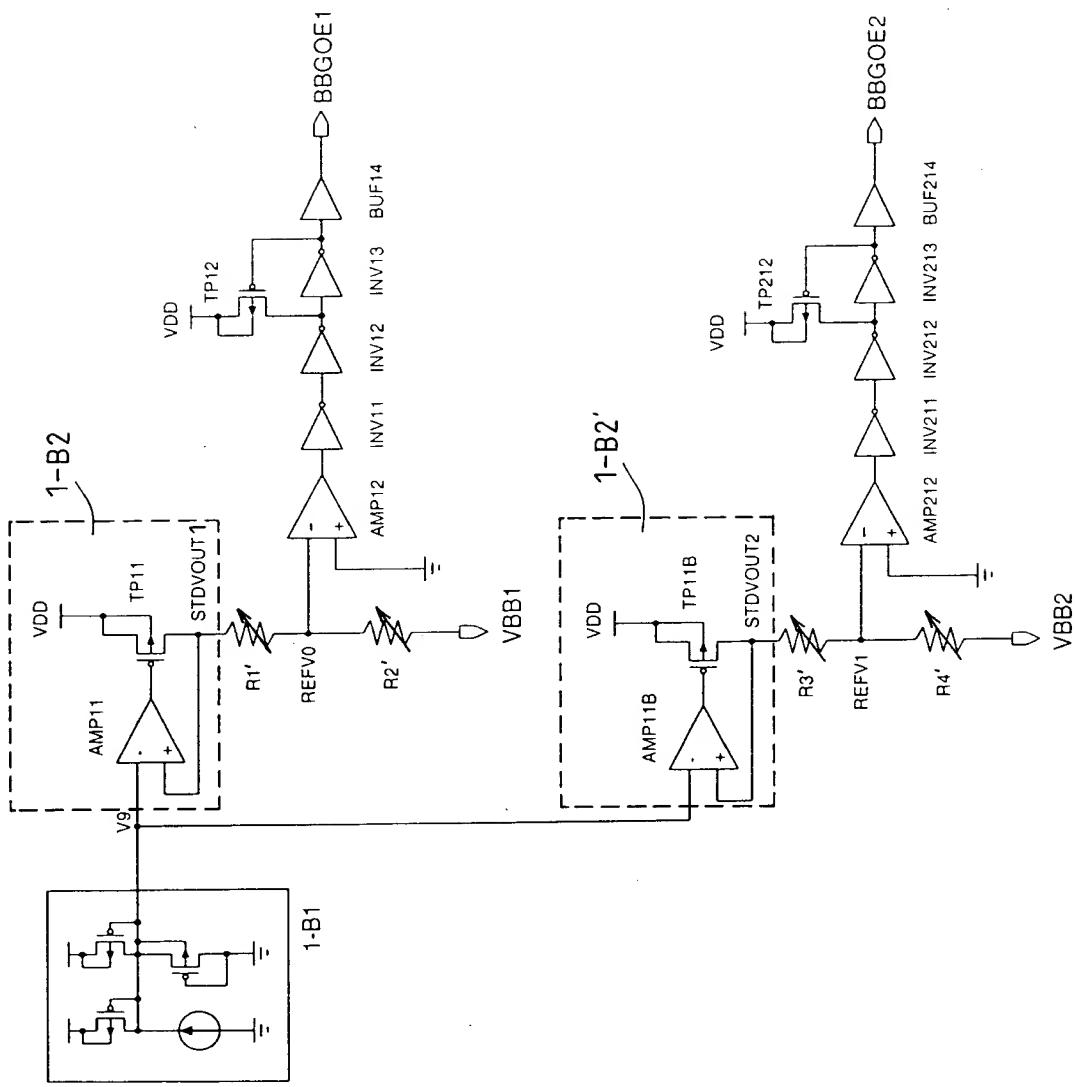


FIG. 8

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FIG. 10 FIG. 10

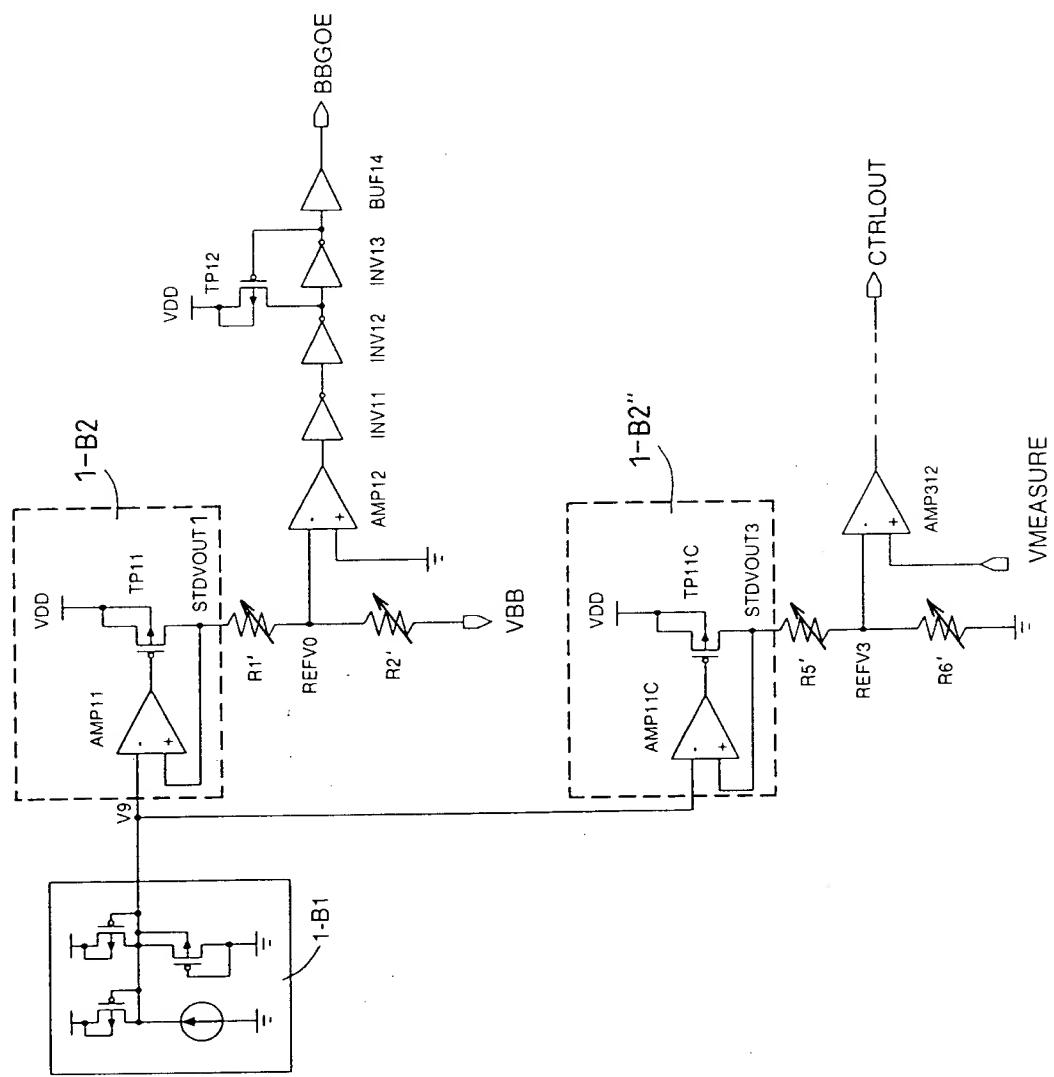


FIG. 10

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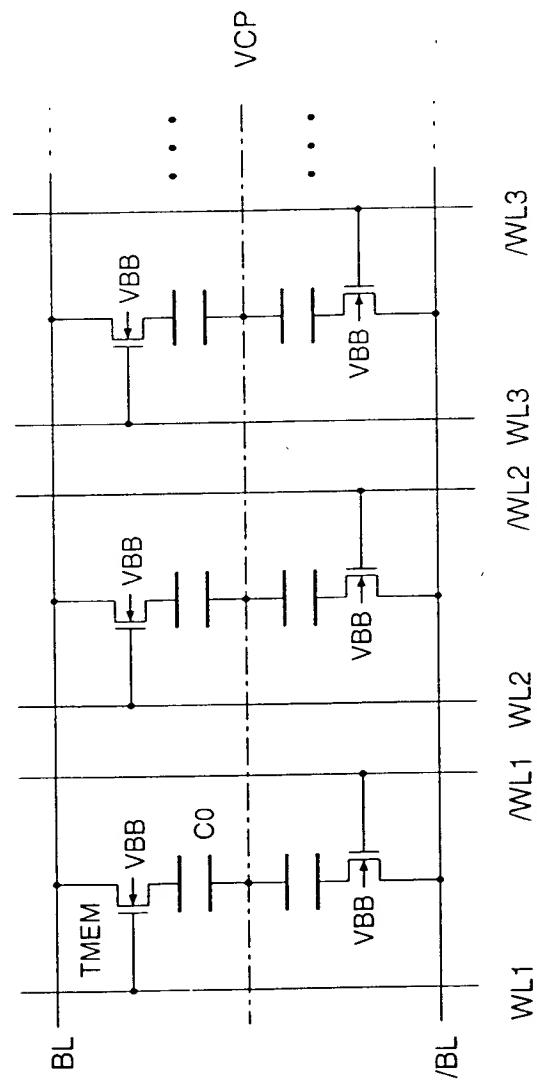


FIG. 11 (PRIOR ART)

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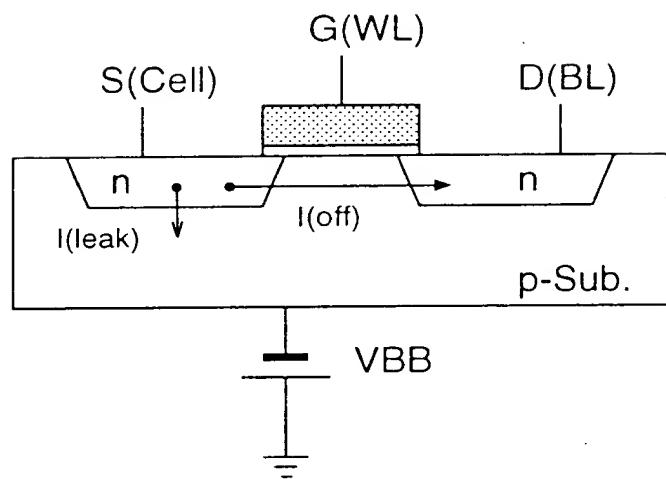


FIG. 12 (PRIOR ART)

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Inventor: KONDO et al.
Docket No.: 10873.713US01
Title: SEMICONDUCTOR INTEGRATED CIRCUIT, TEST METHOD...
Attorney: Douglas P. Mueller
Phone No.: 612.371.5237
Sheet 13 of 18

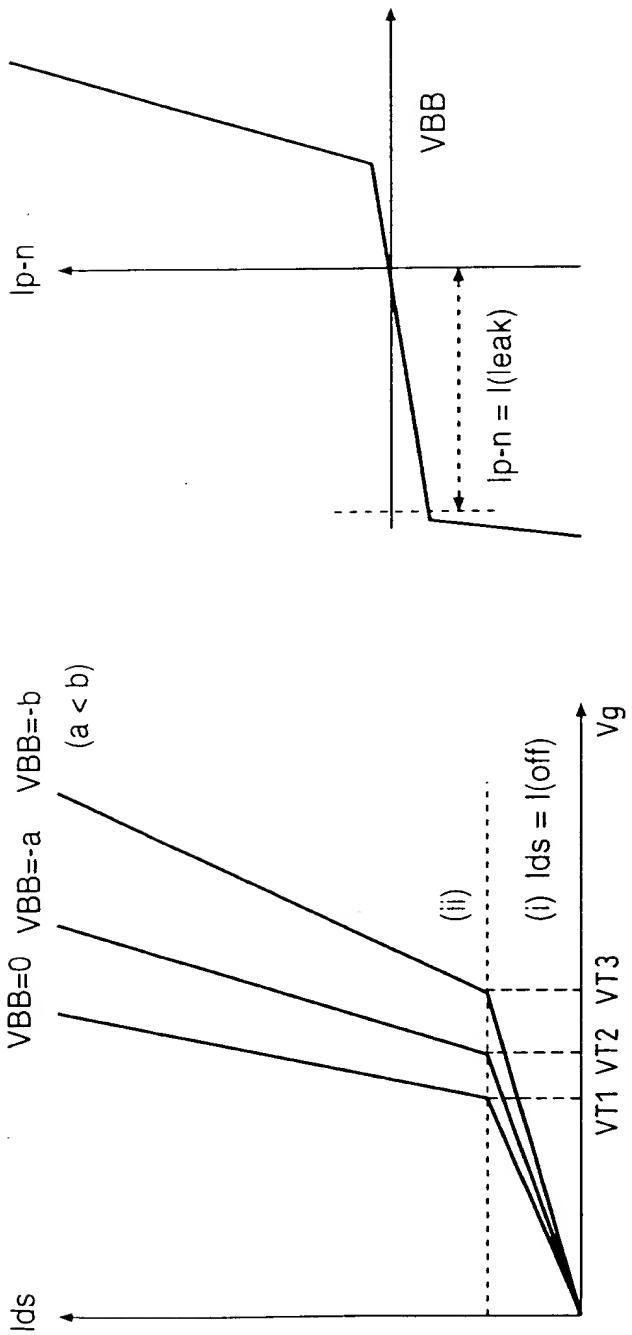


FIG. 13A (PRIOR ART)

FIG. 13B (PRIOR ART)

10010000000000000000000000000000

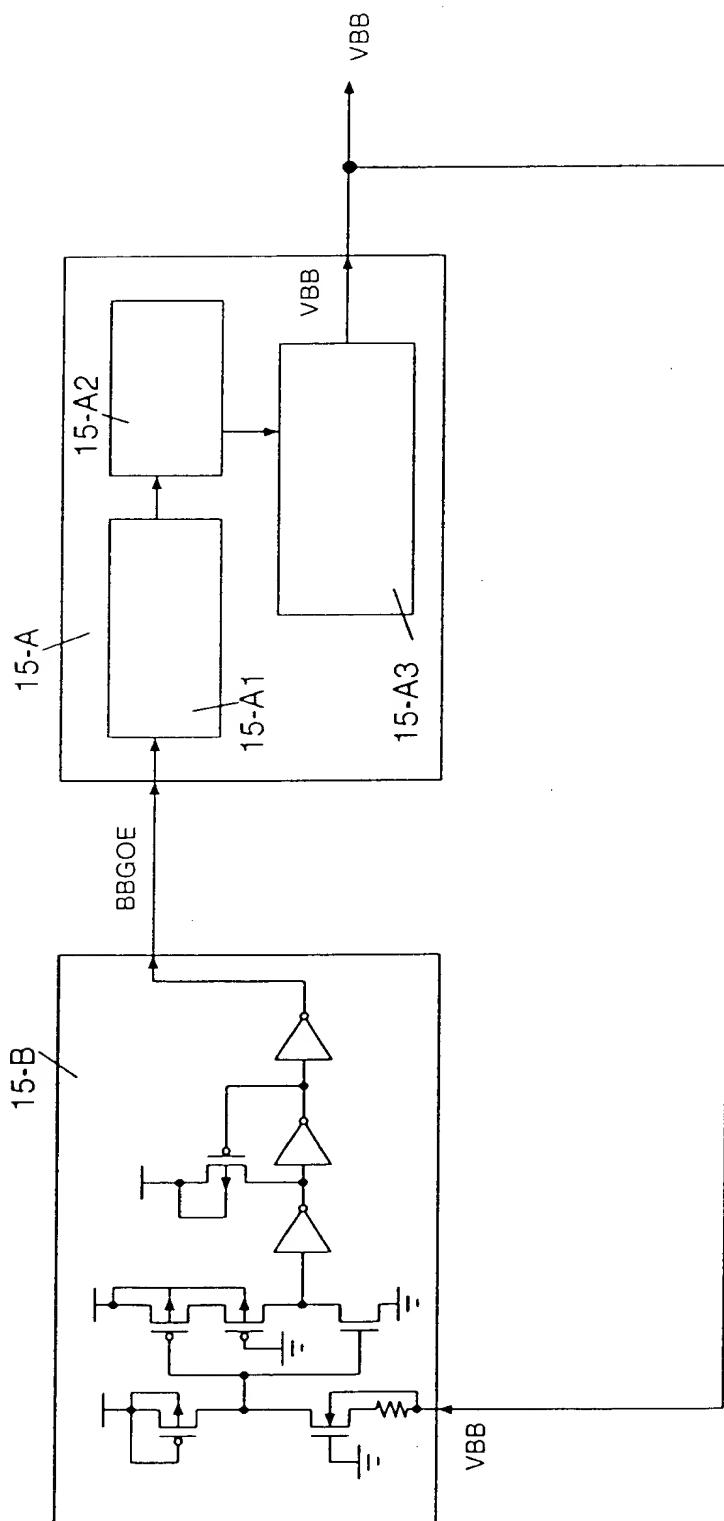


FIG. 14 (PRIOR ART)

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Inventor: KONDO et al.
Docket No.: 10873.713US01
Title: SEMICONDUCTOR INTEGRATED CIRCUIT, TEST METHOD...
Attorney Name: Douglas P. Mueller
Phone No.: 612.371.5237
Sheet 15 of 18

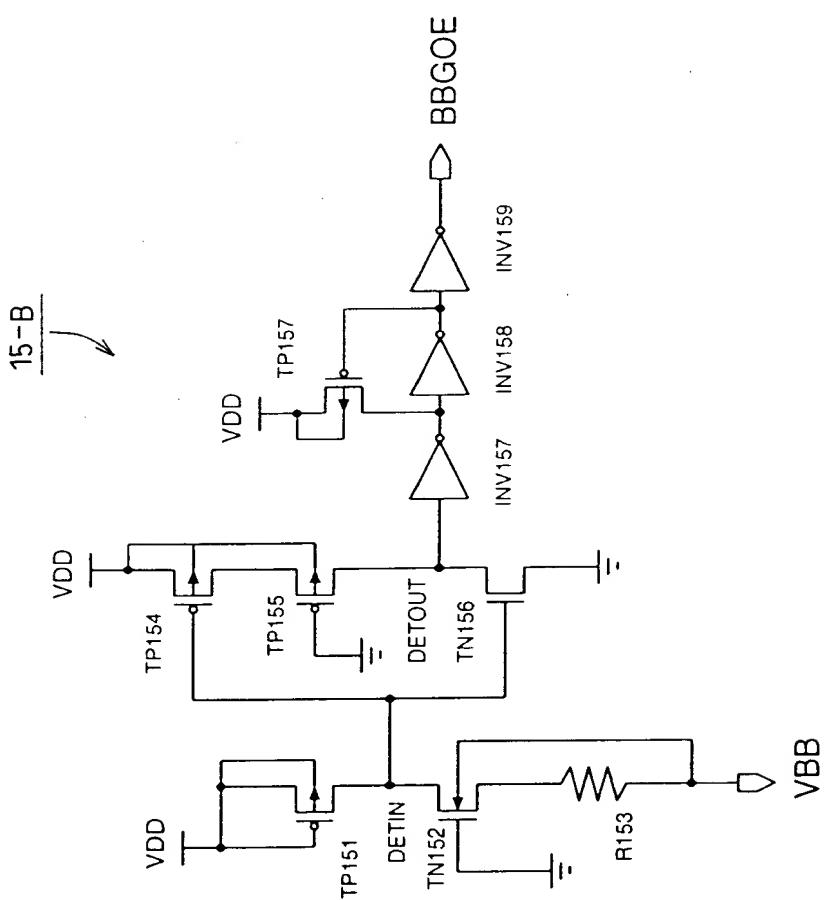


FIG. 15 (PRIOR ART)

7001530 625360

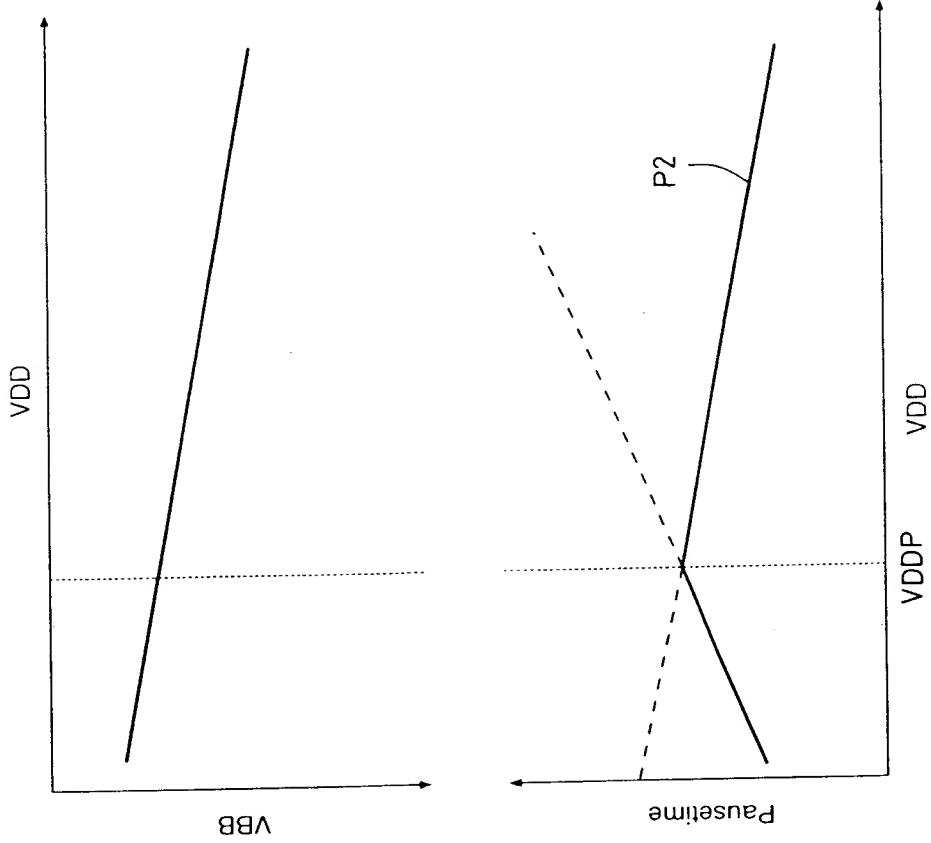


FIG. 16A
(PRIOR ART)

FIG. 16B
(PRIOR ART)

00000000000000000000000000000000

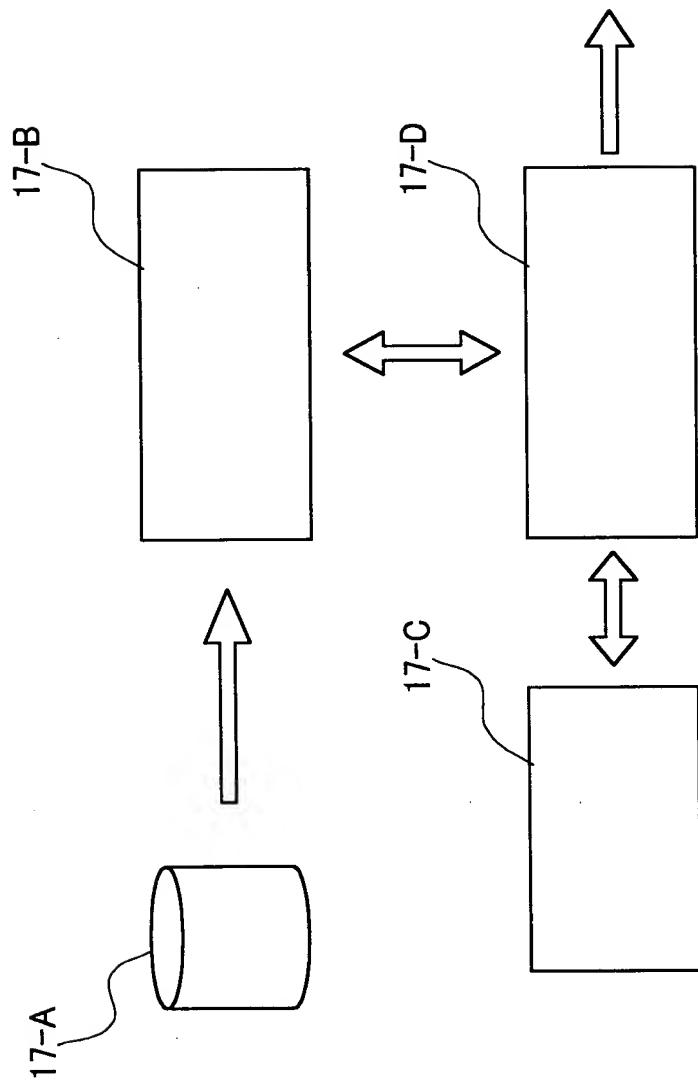
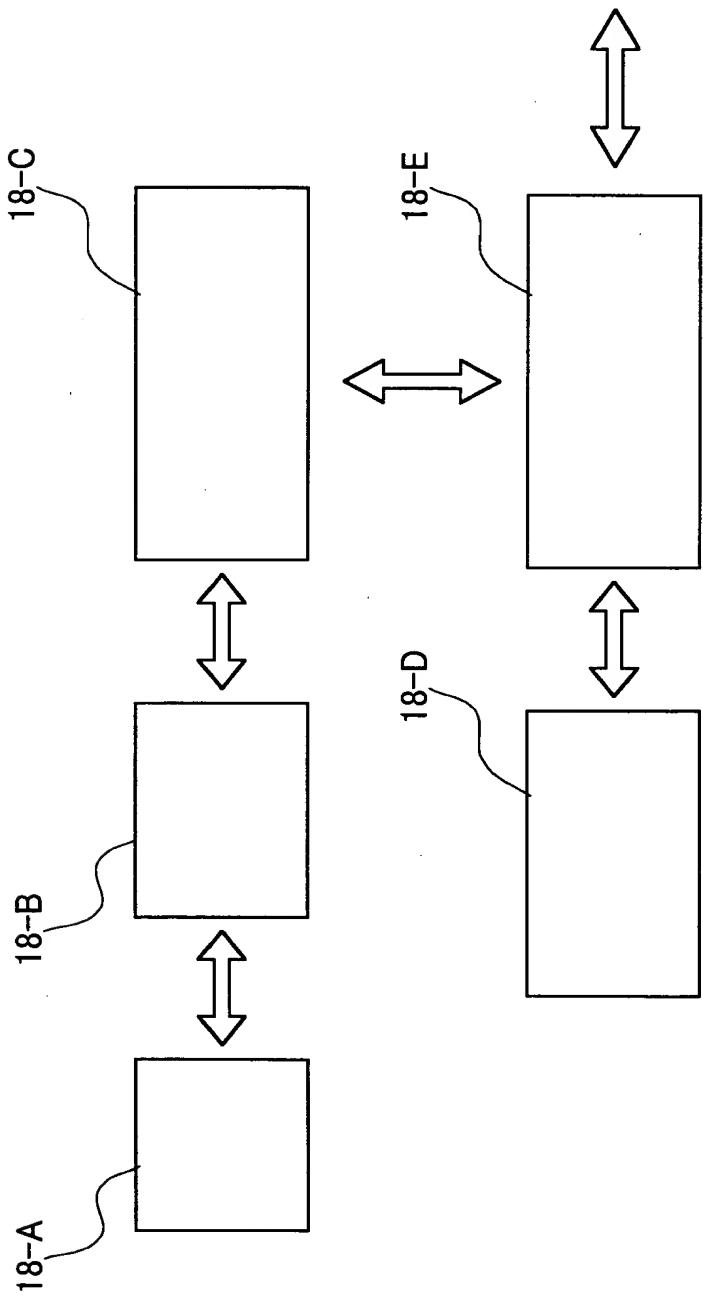


FIG. 17

FIG. 18



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